

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10725378	FAN ET AL.
Examiner	Art Unit	
	PETER COUGHLAN	2129

SEARCHED			
Class	Subclass	Date	Examiner
706	@pd<20031203 and 8, 16, 45, 49	11/2/2007	PDC
703	@pd<20031203 and 2, 9	11/2/2007	PDC
706	@ad<20031203 and @pd>20071102 w/45, 46, 12, 16	4/29/2008	PDC
706	@ad<20031203 and 46	7/14/2008	PDC
707	@ad<20031203 and 1, 3, 4	7/14/2008	PDC

SEARCH NOTES			
Search Notes	Date	Examiner	
East -- @pd<20031203 and inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time, cost, stepwise, progressive	11/2/2007	PDC	
IEEE -- <2003 Fan Wei, Wang Haixun, Yu Phillip, database, subset, accuracy, predictive, time, cost, stepwise, progressive, inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function	11/2/2007	PDC	
Inventors -- Fan Wei, Wang Haixun, Yu Phillip	11/2/2007	PDC	
Google <2003 inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, Fan Wei	11/2/2007	PDC	
Dogpile Fan Wei, Wang Haixun, Yu Phillip, database, segment, subset, accuracy, predictive, time cost stepwise, progressive	11/2/2007	PDC	
East -- @ad<20031203 and @pd>20071102 and dataset, subset, learning model, model, plurality w/subset, increment, divid\$, database, progressive, termination, threshold, build\$, combin\$	4/29/2008	PDC	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner